

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/002,722	CHEN ET AL.	
Examiner	Art Unit	
Tod M. Wang	2611	

SEADCHED						
	SEARCHED					
Class	Subclass	Date	Examiner			
370	324, 503	4/28/2008	TW			
455	437, 502	4/28/2008	TW			
455	515	4/28/2008	TW			
375	324	4/28/2008	TW			
	UPDATED					
375	340	4/28/2008	TW			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
375	340, 324	4/28/2008	TW	
370	324, 503	4/28/2008	TW	
455	437, 502	4/28/2008	TW	
455/515		4/28/2008	TW	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	4/28/2008	TW
ODP - searched and reviewed from east and PALM	4/28/2008	TW
Inventor search - ((Chen with Dayong) or (Lee with Leonard))	4/28/2008	TW
IEEExplor - advance - discontinuous transmission and (SACCH and CDVCC) and pattern	4/28/2008	TW
IEEExplor - author - Chen Dayong, Lee Leonard	4/28/2008	TW